



# Optimization of tungsten oxide films electro-deposited on macroporous silicon for gas sensing applications: Effect of annealing temperature

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Received 24 February 2014; received in revised form 18 July 2014; accepted 6 August 2014

Available online 13 August 2014

## Abstract

Polycrystalline WO<sub>3</sub> films grown on macroporous silicon via electrochemical deposition, have been studied as a function of annealing temperature. The hybrid structure was characterized using scanning electron microscopy, energy-dispersive X-ray spectroscopy, X-ray diffraction and Fourier transform infrared spectroscopy. The microstructure and grain-size of the metal oxide film were found to have significant influence on its electrical and sensing properties. DC conductivity measurements reveal the rectifying behavior of the junction, which is found to increase with annealing temperature. The increased sensitivity of the samples annealed at 700 °C has been attributed to a lower grain size, which contributes to an increase in the depletion region per unit length. An extrapolation of the variation of the resistance  $\Delta R/R_0 = 1.5\%$  predicts possible ethanol sensing up to 1 ppm.

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**Keywords:** Electrodeposition; Gas sensing; Macroporous silicon; Tungsten oxide films

## 1. Introduction

Transition metallic oxides have attracted attention as sensor materials due to their sensitivity towards different kinds of gases [1–4]. Among the different metal oxides, tungsten oxide (WO<sub>x</sub>; this nomenclature is used due to fact that tungsten oxide is a sub-stoichiometric material) is very popular due to its wide band gap and is found to be very useful in areas such as sensing, catalysis, electrochemical industry and field emitters [5–7]. Apart from this, WO<sub>x</sub> possesses electrochromic, optochromic and gasochromic properties [8], which have been applied to design smart windows, electrochromic displays, etc. [9]. In the recent past, scientific community is aggressively looking for cheap, reliable and high-performance sensors for monitoring different gases. Tungsten oxide is an important

semiconductor and is considered as one of the most promising materials for sensing applications. Furthermore, this semiconducting material can be fabricated in thin films to optimize its properties, i.e., to minimize the size of the devices and to integrate with the silicon technology [10].

WO<sub>x</sub> thin films can be prepared by various techniques [11–14] and under different processing conditions, the films usually possess different microstructures and properties. In the recent years, tungsten oxide 1D nanostructures have been mainly grown on silicon or tungsten substrates [15]. Different types of porous substrates have also been used for improving the sensing response of WO<sub>x</sub>, e.g. porous alumina [16] or macroporous silicon (MPS) [17].

In particular porous silicon (PS) has various interesting properties for sensing applications, such as variable surface chemistry and high chemical reactivity [18,19]. Apart from these properties, it has open structure (pores) and large surface area. In general, the versatile nature of PS makes it an ideal

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substrate for potential applications in the field of optoelectronics, photovoltaics, gas sensors, photonics and biomedical applications [20–24].

Several studies of  $\text{WO}_x$  deposited on silicon have been reported, e.g. Fang et al. [25] reported  $\text{WO}_x$  films with different stoichiometries, deposited on Si(111) wafers by pulsed laser deposition technique; Galléa et al. [26] investigated the growth process of  $\text{WO}_x$  nanostructures deposited on Si substrates by a thermal oxidation and constructed a phase growth diagram with the possibility to realize the phase selection and morphology control of  $\text{WO}_x$ . Recently Yan et al. [27] synthesized  $\text{WO}_x$  nanoparticles by sol-gel method and deposited it onto the porous silicon and alumina substrates by dip-coating. Gas sensing tests experimentally demonstrated an improved  $\text{NO}_2$ -sensing with PS substrates decorated with  $\text{WO}_3$  nanoparticles, as compared to  $\text{WO}_x$  deposited on alumina or pristine/pure PS. The same group [28] prepared  $n\text{-WO}_{3-x}/n\text{-PS}$  junctions (by sputtering) for  $\text{NO}_2$  sensing. The sensor exhibited a strong response, fast response/recovery rate, excellent repeatability and good selectivity for efficient detection of  $\text{NO}_2$  at ppb level. Finally, our group [29] has recently studied optical and structural properties of  $\text{WO}_x$  electrodeposited on luminescent meso-porous silicon resulting in an increase of photoluminescence intensity with annealing temperature under nitrogen atmosphere in contrast with air atmosphere.

Ma et al. [15,16,28] have grown different morphologies of tungsten oxide onto MPS for gas sensing application using an expensive, complex and time consuming technique for such deposition [27]. In the present work, optical, structural, electrical and sensing properties of  $\text{WO}_x$  films, deposited onto the MPS substrate through inexpensive, facile and rapid technique (i.e. electrodeposition), have been studied as the function of annealing temperature.

## 2. Experimental

### 2.1. Preparation of porous silicon

MPS was formed by an electrochemical etching of (100)-oriented, boron-doped p-type silicon substrates of resistivity 14–22  $\Omega$  cm, using an electrolyte consisting of 4 wt% hydrofluoric acid (48 wt%) in N,N-Dimethylformamide (ACS reagent,  $\geq 99.8\%$ ). The current density during anodization was kept at 6 mA/cm<sup>2</sup> for 1 h. After fabrication, the samples were rinsed with N,N-Dimethylformamide (DMF) and dried with slow nitrogen flux.

### 2.2. Electrodeposition of $\text{WO}_x$

Thin films of  $\text{WO}_x$  were obtained by electrodeposition in a peroxytungstic acid solution contained in an electrochemical cell with a platinum mesh as the auxiliary electrode and MPS as the working electrode. The working electrode was subjected to a constant cathodic potential of 10 V with different deposition time of 20 and 30 min. The obtained  $\text{WO}_x$  films were homogenous, stable and transparent. Effect of heat treatment on the hybrid structures was studied at 500 and 700 °C for one hour under air atmosphere.

Structural properties of MPS and its composite with  $\text{WO}_x$  were analyzed using a scanning electron microscope (SEM) Hitachi VP-SEM SU1510. The orientation and crystallinity of  $\text{WO}_x$  was analyzed by XRD (XpertPRO) using  $\text{CuK}\alpha$  radiation having wavelength of 1.54 Å. Fourier Transform Infrared spectroscopy (FTIR) model Cary 660 was used for obtaining the information about the chemical bonds formed in the composite structure. The transport characteristics were studied with the help of DC resistance measurements through the lateral and transverse configuration. The gas sensing measurements were carried out in homemade static gas sensing characterization system with the ability to control the ethanol concentration through mass fluxmeters. PPM concentration in the chamber was calculated by the pressure variation using a pirani gauge. To confirm the presence of oxygen vacancies, tungsten oxide powder from Sigma Aldrich of 99.9% purity was used as a reference.

## 3. Results and discussion

Fig. 1 shows top and cross-sectional SEM micrographs of as prepared MPS. These images reveal a uniform surface and squared/rounded shape pores of  $\sim 1$   $\mu\text{m}$  diameter (see inset in Fig. 1a). The corresponding cross-sectional images showing the macroporous structure of the PS layer is shown in Fig. 1b. The silicon wafers were etched for 60 min for the formation of  $\sim 28$   $\mu\text{m}$  thick porous layer.

Fig. 2 shows the top and cross-sectional SEM images of some hybrid structures (MPS- $\text{WO}_x$ ). It is a granular structure distributed all around the pore walls. Magnified view is shown as inset in Fig. 2c. An increase in the deposition time from 20 to 30 min resulted in the formation of some agglomerates on the porous surface as well. The presence of  $\text{WO}_x$  throughout the pore depth was confirmed by energy-dispersive X-ray spectroscopy (EDS) analysis given in the latter part of the manuscript.

Fig. 3 shows the top and cross-section view of  $\text{WO}_x$ -MPS composites after annealing at 500 and 700 °C respectively for 1 h under air atmosphere.  $\text{WO}_x$  is found to cover the pore walls and the adhesion of  $\text{WO}_x$  along the pore depth in the form of thin film is a common feature at both the annealing temperatures. Other notable difference observed at 700 °C is the accumulation of  $\text{WO}_x$  at the bottom of pore (encircled in Fig. 3d). Formation of  $\text{WO}_x$  agglomerates at the bottom of the pores at 700 °C possibly results in the thin  $\text{WO}_x$  layer left on the pore walls.

FTIR is a technique used to obtain information about the chemical bonding in a material. The FTIR spectra taken through an attenuated total reflectance (ATR) accessory of as-deposited and annealed  $\text{WO}_x$ -MPS hybrid structures are shown in Fig. 4. The spectra of as-deposited  $\text{WO}_x$  films (Fig. 4a) reveal absorption bands at 541 and 560  $\text{cm}^{-1}$ . Such values are slightly shifted compared to the bands at 550 and 572  $\text{cm}^{-1}$ , which have been shown in  $\text{WO}_3$  films fabricated by the sol-gel technique and correspond to the peroxy groups W–O–O stretch modes [30]. Fig. 4a also presents a band at 608  $\text{cm}^{-1}$ , which is displaced from 612  $\text{cm}^{-1}$  and can be assigned to the O–W–O stretch, typical of crystalline hydrated

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